

**WAFER ACCEPTANCE TESTING METHOD AND STRUCTURE OF A TEST KEY  
USED IN THE METHOD**

Appl. No. : 10/707,398  
Applicant : Ping Hsu  
Filed : December 10, 2003  
TC/A.U. : 2829  
Examiner : Pert, Evan T  
Docket No. : NTCP0026USA0  
Customer No. : 27765

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Commissioner for Patents  
P.O. Box 1450  
Alexandria VA 22313-1450

**AMENDMENT**

Sir:

5 In response to the Office action of November 17, 2004, please amend the above-identified application as follows:

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 6 of this paper.

10 **Amendments to the Drawings** begin on page 9 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

**Remarks/Arguments** begin on page 10 of this paper.

An **Appendix** including amended drawing figures is attached following page 10 of this paper.